

# DXB-S7BG

## 7B (G) / 7A (G) / W Serial

- The Equipment is a Double-work bench.
- Measurement of the angle in the direction of the end face or reference edge of the wafer/ingot.
- Manually operated measurements, manual judgement of peaks.
- Variety of other sample stages are available, suitable for special size crystals, and special measurement requirements.



## 7BN (G) / 7AN (G) Serial

- The Equipment is a Double-work bench.
- Measurement of the angle of the end face or NOTCH crystal direction of the ingots/wafer.
- Manually operated measurements, manual judgement of peaks.



Item	Specifications
Crystal Diameter	125~200mm, $\pm 1$ mm
Crystal length	Crystal length within 300mm, Wafer Thickness 0.5mm~2.0mm
Measurement angle	0~50°
Accuracy	$\pm 30''$ or $\pm 15''$

### [Extended Functions]:

Difference value display,

Data load,

Data upload,;

Semi-automatic detection,

Crystal detection of

declination, etc.

## Protection

